

Octal D flip-flop

74ABT273

FEATURES

- Eight edge-triggered D-type flip-flops
- Buffered common clock
- Buffered asynchronous Master Reset
- Power-up reset
- See 74ABT377 for clock enable version
- See 74ABT373 for transparent latch version
- See 74ABT374 for 3-State version
- ESD protection exceeds 2000 V per Mil Std 883 Method 3015 and 200 V per machine model.

DESCRIPTION

The 74ABT273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset (MR) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the Low-to-High clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced Low independent of Clock or Data inputs by a Low voltage level on the MR input. The device is useful for applications where the true output only is required and the CP and MR are common elements.

QUICK REFERENCE DATA

| SYMBOL | PARAMETER | CONDITIONS $T_{amb} = 25^{\circ}\text{C}; \text{GND} = 0\text{V}$ | TYPICAL | UNIT |
|------------------------|-------------------------------|--|---------|------|
| t_{PLH} t_{PHL} | Propagation delay CP to Qn | $C_L = 50\text{pF}; V_{CC} = 5\text{V}$ | 5.3 | ns |
| C_{IN} | Input capacitance | $V_I = 0\text{V or } V_{CC}$ | 3.5 | pF |
| I_{CC} | Total supply current | Outputs High; $V_{CC} = 5.5\text{V}$ | 500 | nA |

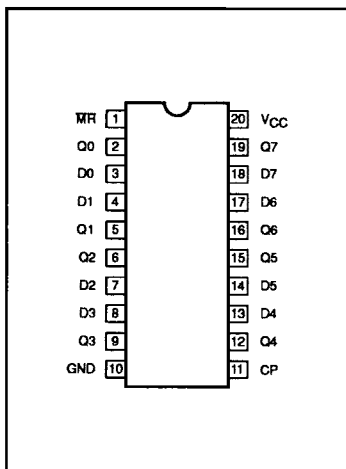
ORDERING INFORMATION

| PACKAGES | TEMPERATURE RANGE | ORDER CODE | DRAWING NUMBER |
|--------------------------------|-------------------|------------|----------------|
| 20-pin plastic DIP | -40°C to +85°C | 74ABT273N | 0408B |
| 20-pin plastic SOL | -40°C to +85°C | 74ABT273D | 0172D |
| 20-pin plastic SSOP Type II | -40°C to +85°C | 74ABT273DB | 1640A |

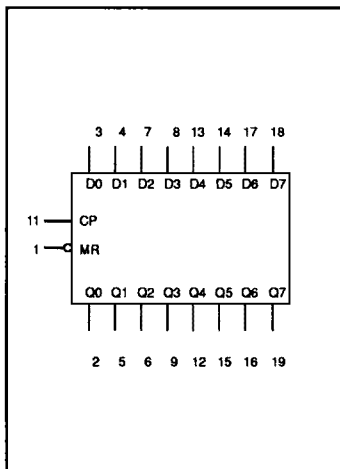
PIN DESCRIPTION

| PIN NUMBER | SYMBOL | NAME AND FUNCTION |
|-------------------------------|----------|--|
| 11 | CP | Clock pulse input (active rising edge) |
| 3, 4, 7, 8, 13, 14, 17, 18 | D0 – D7 | Data inputs |
| 2, 5, 6, 9, 12, 15, 16, 19 | Q0 – Q7 | Data outputs |
| 1 | MR | Master Reset input (active-Low) |
| 10 | GND | Ground (0V) |
| 20 | V_{CC} | Positive supply voltage |

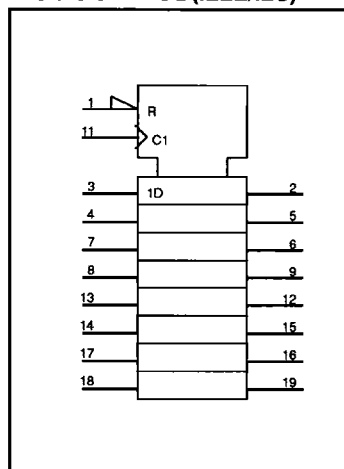
PIN CONFIGURATION



LOGIC SYMBOL



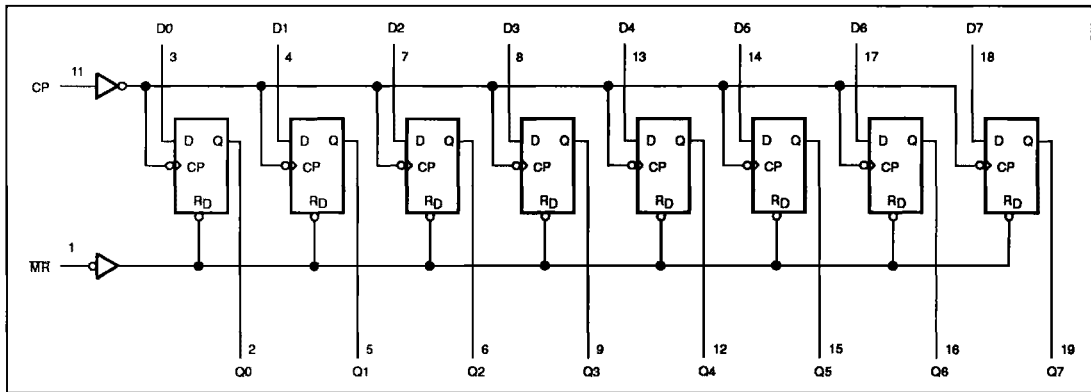
LOGIC SYMBOL (IEEE/IEC)



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LOGIC DIAGRAM



FUNCTION TABLE

| INPUTS | | | OUTPUTS | OPERATING MODE |
|--------|----|----------------|---------------------------------|----------------|
| MR | CP | D _n | Q ₀ – Q ₇ | |
| L | X | X | L | Reset (clear) |
| H | ↑ | h | H | Load "1" |
| H | ↑ | l | L | Load "0" |

- H = High voltage level
- h = High voltage level one set-up time prior to the Low-to-High clock transition
- L = Low voltage level
- l = Low voltage level one set-up time prior to the Low-to-High clock transition
- X = Don't care
- ↑ = Low-to-High clock transition

ABSOLUTE MAXIMUM RATINGS^{1, 2}

| SYMBOL | PARAMETER | CONDITIONS | RATING | UNIT |
|------------------|--------------------------------|-----------------------------|--------------|------|
| V _{CC} | DC supply voltage | | -0.5 to +7.0 | V |
| I _{IK} | DC input diode current | V _I < 0 | -18 | mA |
| V _I | DC input voltage ³ | | -1.2 to +7.0 | V |
| I _{OK} | DC output diode current | V _O < 0 | -50 | mA |
| V _{OUT} | DC output voltage ³ | output in Off or High state | -0.5 to +5.5 | V |
| I _{OUT} | DC output current | output in Low state | 128 | mA |
| T _{stg} | Storage temperature range | | -65 to 150 | °C |

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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RECOMMENDED OPERATING CONDITIONS

| SYMBOL | PARAMETER | LIMITS | | UNIT |
|------------------|--------------------------------------|--------|-----------------|------|
| | | Min | Max | |
| V _{CC} | DC supply voltage | 4.5 | 5.5 | V |
| V _I | Input voltage | 0 | V _{CC} | V |
| V _{IH} | High-level input voltage | 2.0 | | V |
| V _{IL} | Low-level input voltage | | 0.8 | V |
| I _{OH} | High-level output current | | -32 | mA |
| I _{OL} | Low-level output current | | 64 | mA |
| Δt/ΔV | Input transition rise or fall rate | 0 | 5 | ns/V |
| T _{amb} | Operating free-air temperature range | -40 | +85 | °C |

DC ELECTRICAL CHARACTERISTICS

| SYMBOL | PARAMETER | TEST CONDITIONS | LIMITS | | | | | UNIT |
|-------------------|--|--|--------------------------|-------|------|-----------------------------------|------|------|
| | | | T _{amb} = +25°C | | | T _{amb} = -40°C to +85°C | | |
| | | | Min | Typ | Max | Min | Max | |
| V _{IK} | Input clamp voltage | V _{CC} = 4.5V; I _{IK} = -18mA | | -0.9 | -1.2 | | -1.2 | V |
| V _{OH} | High-level output voltage | V _{CC} = 4.5V; I _{OH} = -3mA; V _I = V _{IL} or V _{IH} | 2.5 | 2.9 | | 2.5 | | |
| | | V _{CC} = 5.0V; I _{OH} = -3mA; V _I = V _{IL} or V _{IH} | 3.0 | 3.4 | | 3.0 | | V |
| | | V _{CC} = 4.5V; I _{OH} = -32mA; V _I = V _{IL} or V _{IH} | 2.0 | 2.4 | | 2.0 | | |
| V _{OL} | Low-level output voltage | V _{CC} = 4.5V; I _{OL} = 64mA; V _I = V _{IL} or V _{IH} | | 0.42 | 0.55 | | 0.55 | V |
| V _{RST} | Power-up output low voltage ³ | V _{CC} = 5.5V; I _O = 1mA; V _I = GND or V _{CC} | | 0.13 | 0.55 | | 0.55 | V |
| I _I | Input leakage current | V _{CC} = 5.5V; V _I = GND or 5.5V | | ±0.01 | ±1.0 | | ±1.0 | μA |
| I _{OFF} | Power-off leakage current | V _{CC} = 0.0V; V _O or V _I ≤ 4.5V | | ±5.0 | ±100 | | ±100 | μA |
| I _{CEx} | Output High leakage current | V _{CC} = 5.5V; V _O = 5.5V; V _I = GND or V _{CC} | | 5.0 | 50 | | 50 | μA |
| I _O | Output current ¹ | V _{CC} = 5.5V; V _O = 2.5V | -50 | -100 | -180 | -50 | -180 | mA |
| I _{CC} H | Quiescent supply current | V _{CC} = 5.5V; Outputs High, V _I = GND or V _{CC} | | 0.5 | 50 | | 50 | μA |
| I _{CC} L | | V _{CC} = 5.5V; Outputs Low, V _I = GND or V _{CC} | | 24 | 30 | | 30 | mA |
| ΔI _{CC} | Additional supply current per input pin ² | V _{CC} = 5.5V; One data input at 3.4V, other inputs at V _{CC} or GND | | 0.5 | 1.5 | | 1.5 | mA |

NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- This is the increase in supply current for each input at 3.4V.
- For valid test results, data must not be loaded into the flip-flops (or latches) after applying the power.

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AC CHARACTERISTICSGND = 0V; $t_R = t_F = 2.5\text{ns}$; $C_L = 50\text{pF}$, $R_L = 500\Omega$

| SYMBOL | PARAMETER | WAVEFORM | LIMITS | | | | | UNIT |
|--------------------------------------|-------------------------------|----------|--|------------|------------|--|------------|------|
| | | | $T_{\text{amb}} = +25^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V}$ | | | $T_{\text{amb}} = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V} \pm 0.5\text{V}$ | | |
| | | | Min | Typ | Max | Min | Max | |
| f_{MAX} | Maximum clock frequency | 1 | 150 | 200 | | 150 | | MHz |
| t_{PLH} t_{PHL} | Propagation delay CP to Qn | 1 | 2.5 3.3 | 4.5 5.3 | 6.0 6.8 | 2.5 3.3 | 6.5 7.3 | ns |
| t_{PHL} | Propagation delay MR to Qn | 2 | 2.5 | 4.5 | 6.0 | 2.5 | 7.0 | ns |

AC SETUP REQUIREMENTSGND = 0V; $t_R = t_F = 2.5\text{ns}$; $C_L = 50\text{pF}$, $R_L = 500\Omega$

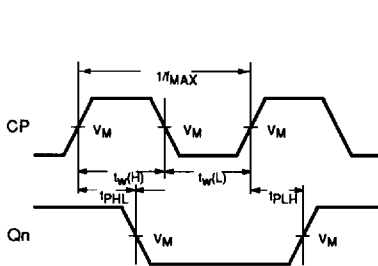
| SYMBOL | PARAMETER | WAVEFORM | LIMITS | | | | | UNIT |
|------------------------------------|-------------------------------------|----------|--|--------------|--|--|--|------|
| | | | $T_{\text{amb}} = +25^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V}$ | | $T_{\text{amb}} = -40^\circ\text{C to } +85^\circ\text{C}$ $V_{\text{CC}} = +5.0\text{V} \pm 0.5\text{V}$ | | | |
| | | | Min | Typ | Min | | | |
| $t_s(\text{H})$ $t_s(\text{L})$ | Setup time, High or Low Dn to CP | 3 | 2.0 2.5 | 0.8 0.7 | 2.0 2.5 | | | |
| $t_h(\text{H})$ $t_h(\text{L})$ | Hold time, High or Low Dn to CP | 3 | 0.7 0.7 | -0.5 -0.5 | 0.7 0.7 | | | ns |
| $t_w(\text{H})$ $t_w(\text{L})$ | Clock pulse width High or Low | 1 | 3.3 3.3 | 2.4 2.9 | 3.3 3.3 | | | ns |
| $t_w(\text{L})$ | Master Reset pulse width, Low | 2 | 3.3 | 2.8 | 3.3 | | | ns |
| t_{REC} | Recovery time MR to CP | 2 | 2.0 | 0.7 | 2.0 | | | ns |

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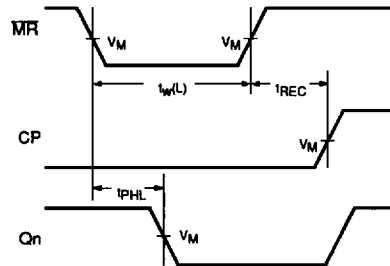
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AC WAVEFORMS

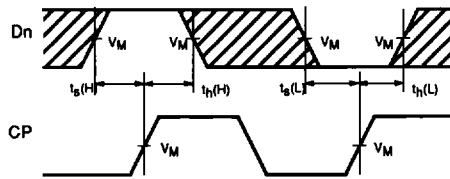
$V_M = 1.5V$, $V_{IN} = GND$ to $3.0V$



Waveform 1. Propagation Delay, Clock Input to Output, Clock Pulse Width, and Maximum Clock Frequency



Waveform 2. Master Reset Pulse Width, Master Reset to Output Delay and Master Reset to Clock Recovery Time



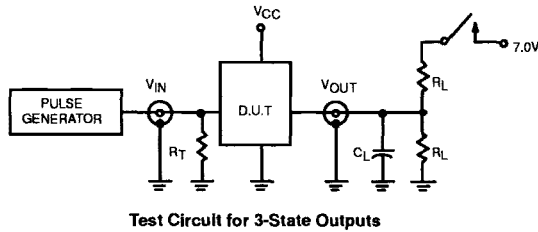
Waveform 3. Data Setup and Hold Times

NOTE: The shaded areas indicate when the input is permitted to change for predictable output performance.

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TEST CIRCUIT AND WAVEFORMS

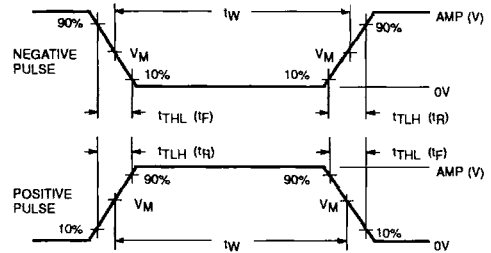


SWITCH POSITION

| TEST | SWITCH |
|------|--------|
| All | open |

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.



| FAMILY | INPUT PULSE REQUIREMENTS | | | | |
|--------|--------------------------|-----------|-------|-------|-------|
| | Amplitude | Rep. Rate | t_w | t_R | t_F |
| 74ABT | 3.0V | 1MHz | 500ns | 2.5ns | 2.5ns |